

Search Notes

Application/Control No.

09/967,084

Examiner

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Applicant(s)/Patent under
Reexamination

BEIER ET AL.

Art Unit

2155

SEARCHED

Class	Subclass	Date	Examiner
709	104, 212, 238	3/17/2004	MW
711	113, 118	3/17/2004	MW
709	212, 238	2/9/2006	MW
709	212, 214, 215, 245	7/14/2006	MW
711	3, 118, 147, 213, 216, 221	7/14/2006	MW
707	205	7/14/2006	MW
709	212, 214, 215, 245	11/30/2006	MW
711	3, 118, 147, 213, 216, 221	11/30/2006	MW
707	205	11/30/2006	MW
709	212, 214, 215, 238, 242	4/26/2007	MW
711	3, 118, 147, 213, 216, 221	4/26/2007	MW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
709	238	4/26/2007	MW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	3/17/2004	MW
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	9/7/2005	MW
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	2/9/2006	MW
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	7/14/2006	MW
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	11/30/2006	MW
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	4/26/2007	MW
NPL SEARCH: IEEE	4/26/2007	MW